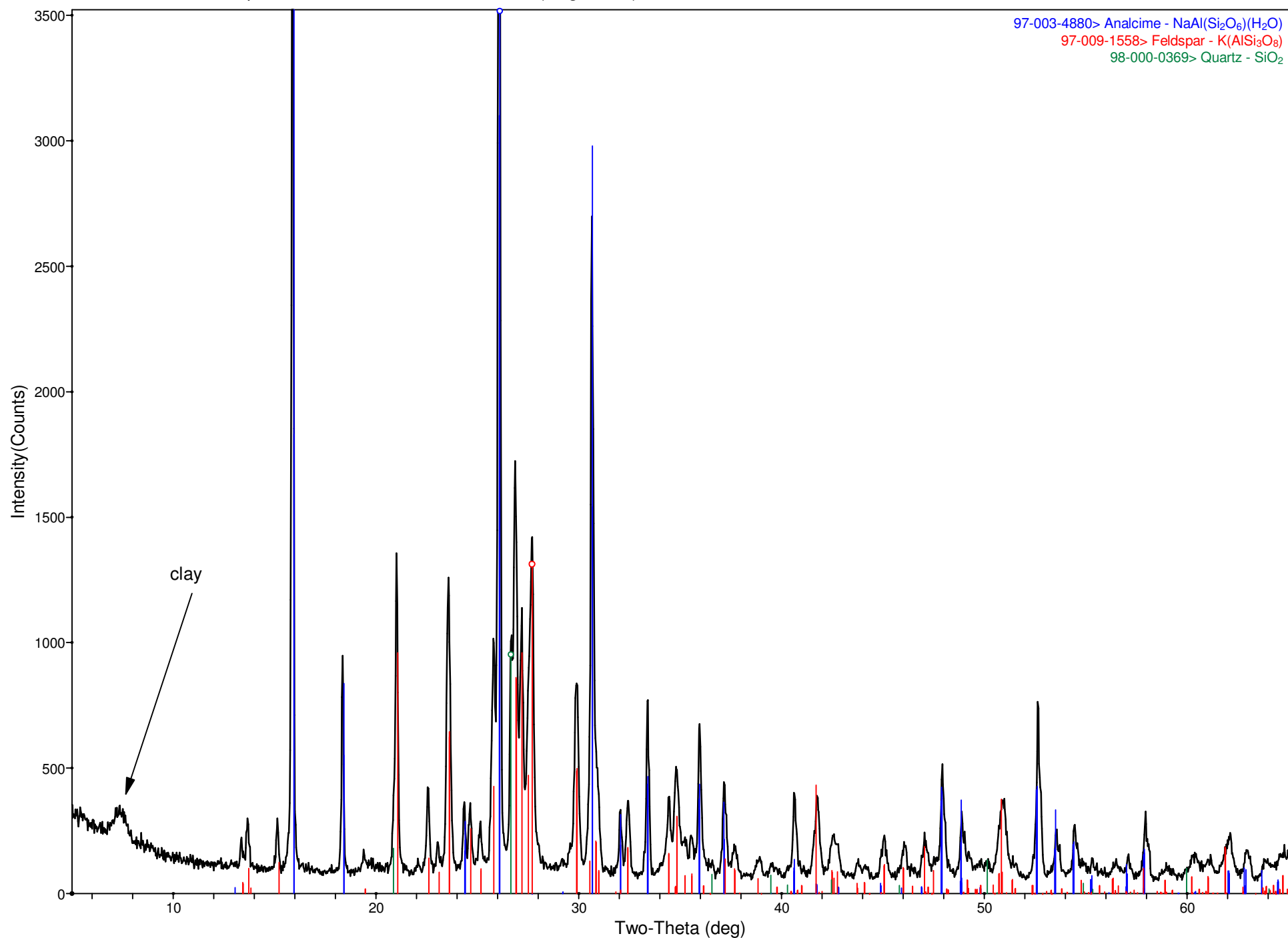


Analcime from Mumpton Collection #25606 Barstow, CA (beige color)



Whole Pattern Fitting and Rietveld Refinement

FILE: [std Mumpton Alancime 25606.raw] beige analcime u
 SCAN: 5.0/65.0/0.03/2.1(sec), Cu, I(p)=6276, 01/14/09 02:30p
 PROC: [C:\Documents and Settings\wbenze\My Documents\AAA Data Processing\901003 Swayze leucite\std Mumpton Alancime...

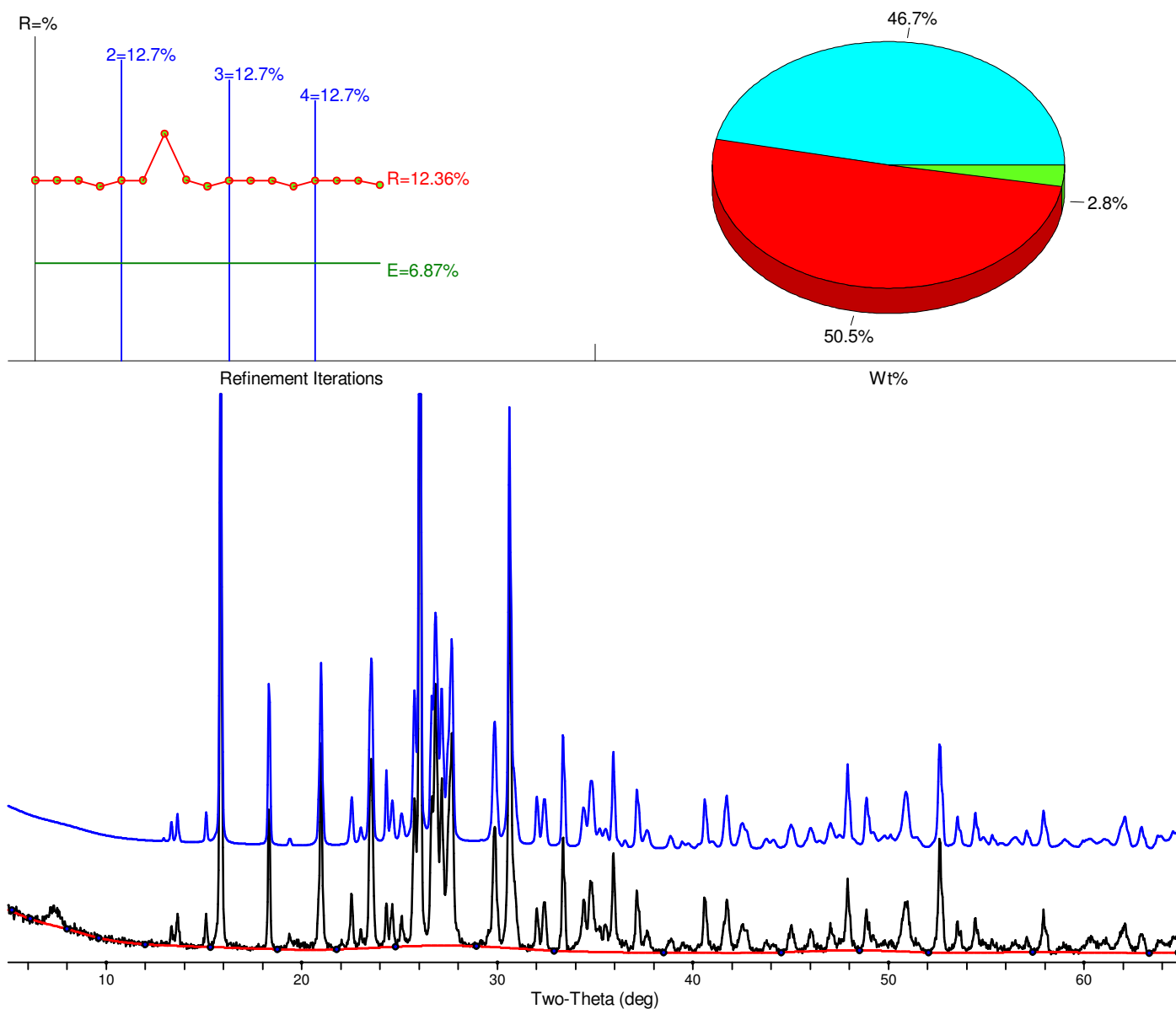
- | | |
|--|--|
| <input checked="" type="checkbox"/> K-alpha2 Peak Present | [Diffractometer LP] Two-Theta Range of Fit = 5.0 - 65.0(deg) |
| <input checked="" type="checkbox"/> Allow Negative Isotropic B | <input checked="" type="checkbox"/> Zero Offset of Goniometer - 2Theta = -0.178411(0.069264) |
| <input checked="" type="checkbox"/> Allow Negative Occupancy | <input checked="" type="checkbox"/> Specimen Displacement - Cos(Theta) = 0.18956(0.071621) |
| <input checked="" type="checkbox"/> Apply Anomalous Scattering | <input checked="" type="checkbox"/> Axial Divergence - Cot(2Theta) = 0.00228(0.001623) |
| <input checked="" type="checkbox"/> Use Isotropic B Value Only | <input type="checkbox"/> Monochromator Correction for LP Factor = 1.0 |
| | <input type="checkbox"/> K-alpha2/K-alpha1 Intensity Ratio = 0.5 |

Profile Shape Function (PSF) for All Phases: pseudo-Voigt, Fixed-BG, Lambda=1.54059Å (Cu/K-alpha1)

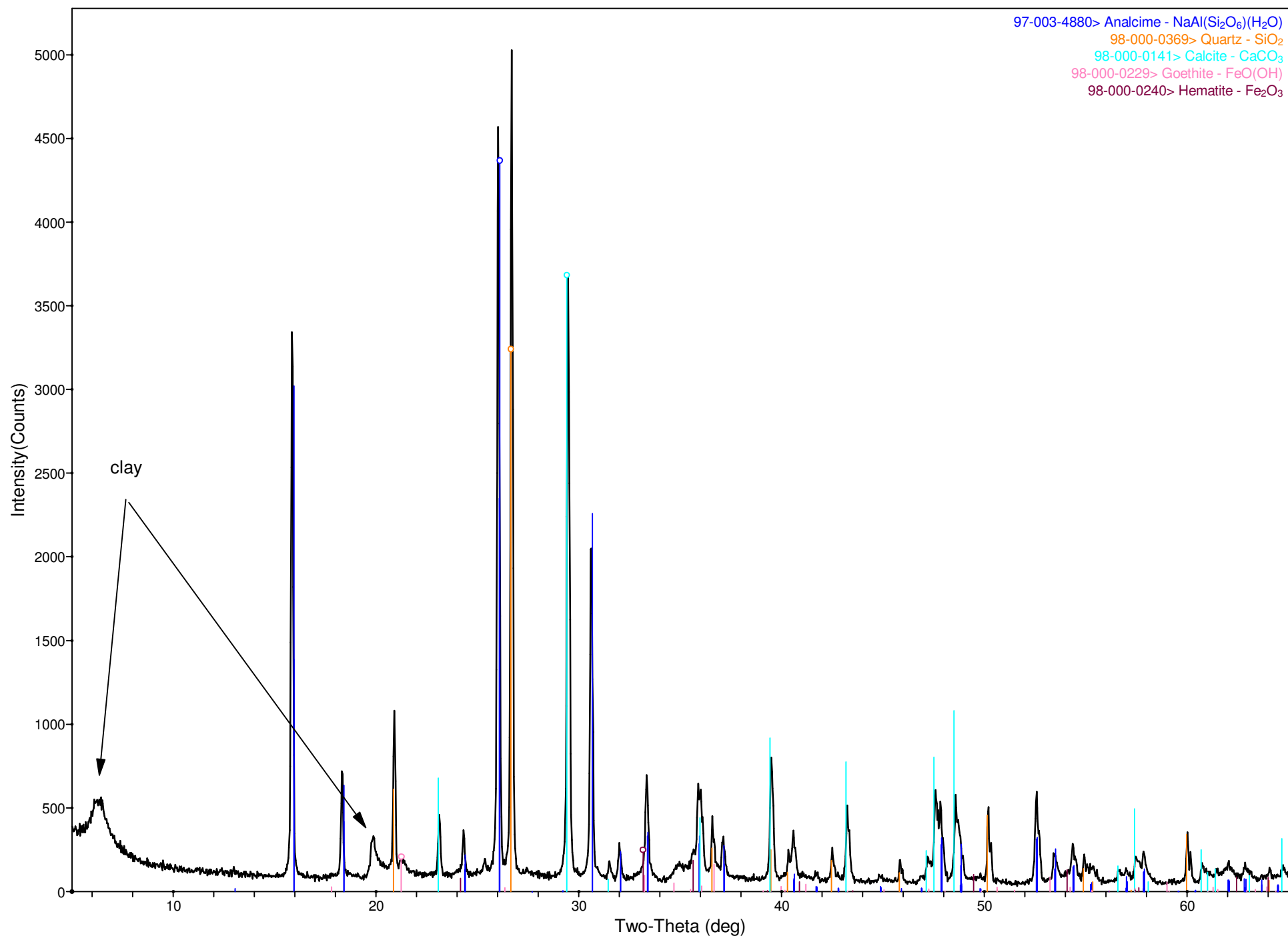
Phase ID (3)	Source	I/Ic	Wt%	#L
■ Analcime 1Q - NaAl(Si ₂ O ₆)(H ₂ O)	PDF#97-003-4880	1.29(0%)	46.7 (0.4)	118
■ Feldspar - K(AlSi ₃ O ₈)	PDF#97-009-1558	0.59(0%)	50.5 (0.4)	240
■ Quartz - SiO ₂	PDF#98-000-0369	4.22(0%)	2.8 (0.1)	40

XRF(Wt%): K=7.1%, Si=28.6%, Al=10.7%, Na=4.9%, O=48.7%

NOTE: Fitting Halted at Iteration 17(4): R=12.36% (E=6.87%, R/E=1.8, P=27, EPS=0.5)



Analcimie from Mumpton Collection #25607 Vernal UT (red)



Whole Pattern Fitting and Rietveld Refinement

FILE: [std Mumpton Analcime 25607.raw] red analcime u
 SCAN: 5.0/65.0/0.03/2.1(sec), Cu, I(p)=5026, 01/14/09 12:43p
 PROC: [WPF Control File]

- | | |
|--|---|
| <input checked="" type="checkbox"/> K-alpha2 Peak Present | [Diffractometer LP] Two-Theta Range of Fit = 5.0 - 65.0(deg) |
| <input checked="" type="checkbox"/> Allow Negative Isotropic B | <input checked="" type="checkbox"/> Zero Offset of Goniometer - 2Theta = 0.240454(0.361718) |
| <input checked="" type="checkbox"/> Allow Negative Occupancy | <input checked="" type="checkbox"/> Specimen Displacement - Cos(Theta) = -0.17169(0.336095) |
| <input checked="" type="checkbox"/> Apply Anomalous Scattering | <input checked="" type="checkbox"/> Axial Divergence - Cot(2Theta) = -0.00624(0.004487) |
| <input checked="" type="checkbox"/> Use Isotropic B Value Only | <input type="checkbox"/> Monochromator Correction for LP Factor = 1.0 |
| | <input type="checkbox"/> K-alpha2/K-alpha1 Intensity Ratio = 0.5 |

Profile Shape Function (PSF) for All Phases: pseudo-Voigt, Polynomial(2), Lambda=1.54059Å (Cu/K-alpha1)

Phase ID (5)	Source	I/Ic	Wt%	#L
■ Analcime 1Q - NaAl(Si ₂ O ₆)(H ₂ O)	PDF#97-003-4880	1.29(5%)	46.0 (2.6)	112
■ Quartz - SiO ₂	PDF#98-000-0369	4.21(0%)	21.5 (0.6)	40
■ Calcite - CaCO ₃	PDF#98-000-0141	2.97(0%)	24.2 (0.7)	17
■ Goethite - FeO(OH)	PDF#98-000-0229	2.63(0%)	6.0 (0.4)	32
■ Hematite - Fe ₂ O ₃	PDF#98-000-0240	3.14(0%)	2.2 (0.2)	13

XRF(Wt%): Fe=5.4%, Ca=9.7%, Si=21.8%, Al=5.6%, Na=4.8%, O=49.3%, C=2.9%, H=0.4%

NOTE: Fitting Halted at Iteration 24(4): R=17.22% (E=7.24%, R/E=2.38, P=40, EPS=0.5)

